

<b>Notice of References Cited</b>	Application/Control No. 10/764,241		Applicant(s)/Patent Under Reexamination CHANG, CHIEN-JEN	
	Examiner Thomas E. Scott Jr.		Art Unit 2609	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0025718 A1	02-2003	Mori, Makiko	345/690
*	B	US-2003/0151565 A1	08-2003	Kim et al.	345/60
*	C	US-2002/0180680 A1	12-2002	Moon, Seung-Hwan	345/89
*	D	US-2003/0058211 A1	03-2003	Kim et al.	345/89
*	E	US-2001/0033260 A1	10-2001	Nishitani et al.	345/87
*	F	US-2002/0063670 A1	05-2002	Yoshinaga et al.	345/87
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.